



# GSX18N65E

## MOSFET

Metal Oxide Semiconductor Field Effect Transistor

Super Junction MOSFET

650V Super Junction Power Transistor

GSX18N65E

Data Sheet

Ver 1.1

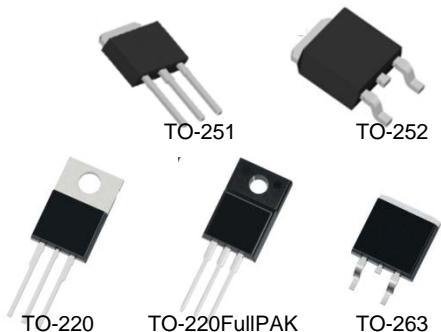
2019-3-20

# 650V 18A Power MOSFET

## ■ Description

Group Semiconductor (GS) has series Multi-EPI Super-Junction power MOSFET platforms for voltage up to 500V to 1000V, both with design service and manufacturing capability, including cell, termination design and simulation.

The GS 650V 18A Power MOSFET is a Low voltage N channel Multi-EPI Super-Junction power MOSFET sample with advanced technology to have better characteristics, such as fast switching time, low C<sub>iss</sub> and C<sub>rss</sub>, low on resistance and excellent avalanche characteristics, making it especially suitable for applications which require superior power density and outstanding efficiency.



## ■ Features

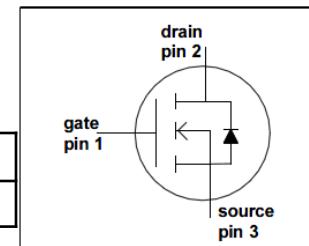
RDS(ON)=0.25Ω @VGS = 10V

VDS = 650V

ID (@ VGS=10V) = 9A

## ■ PKG

GSA18N65E	GSP18N65E	GSB18N65E	GSD18N65E	GSS18N65E
TO-220FullPak	TO-220	TO-263	TO-252	TO-251



## ■ Absolute Maximum Ratings (TC = 25° C, unless otherwise specified)

Symbol	Parameter	GSP18N65E	GSA18N65E	Unit
V <sub>DSS</sub>	Drain-Source Voltage	650		V
I <sub>D</sub>	Drain Current - Continuous (TC = 25°C) - Continuous (TC = 100°C)	18*	13*	A
I <sub>DM</sub>	Drain Current - Pulsed (Note 1)	55		A
V <sub>GSS</sub>	Gate-Source voltage	±30		V
E <sub>A</sub>	Single Pulsed Avalanche Energy (Note 2)	320		mJ
I <sub>AR</sub>	Avalanche Current (Note 1)	3		A
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)	2		mJ
dV/dt	Peak Diode Recovery dV/dt (Note 3)	15		V/ns
dV <sub>Ds</sub> /dt	Drain Source voltage slope (V <sub>Ds</sub> =480V)	50		V/ns
P <sub>D</sub>	Power Dissipation (TC = 25°C)	151	35	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range	-55 to +150		°C
T <sub>L</sub>	Max. Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds	300		°C

## ■ Thermal Characteristics

Symbol	Parameter	GSA18N65E	GSP18N65E	Unit
R <sub>θJC</sub>	Thermal Resistance, Junction-to-Case	1.2	1.2	°C/W
R <sub>θCS</sub>	Thermal Resistance, Case-to-Sink Typ.	0.5	0.5	°C/W
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	62	62	°C/W

Symbol	Parameter	Value (TO220)	Unit
R <sub>θJA</sub> <sup>(6)</sup>	Maximum Junction-to-Ambient	82	°C/W
R <sub>θCS</sub> <sup>(6)</sup>	Maximum Case-to-sink	0.6	°C/W
R <sub>θJC</sub> <sup>(7),(8)</sup>	Maximum Junction-to-Case θ	4.1	°C/W

1. The power dissipation PD is based on TJ(MAX)=150° C in a TO251 package, using junction-to-case thermal resistance.
2. Repetitive rating, pulse width limited by junction temperature TJ(MAX)=150° C.
3. L=1mH, Starting TJ=25° C.
4. L = 10mH, starting TJ = 25° C.
5. L=60mH, starting TJ = 25° C.
6. The tests are performed with the device with T A =25° C.
7. The R □ JA is the sum of the thermal impedance from junction to case R □ JC and case to ambient.
8. These curves are based on the junction-to-case thermal impedance, assuming a maximum junction temperature of TJ(MAX)=150° C.

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## ■ Electrical Characteristics (TJ=25° C unless otherwise specified)

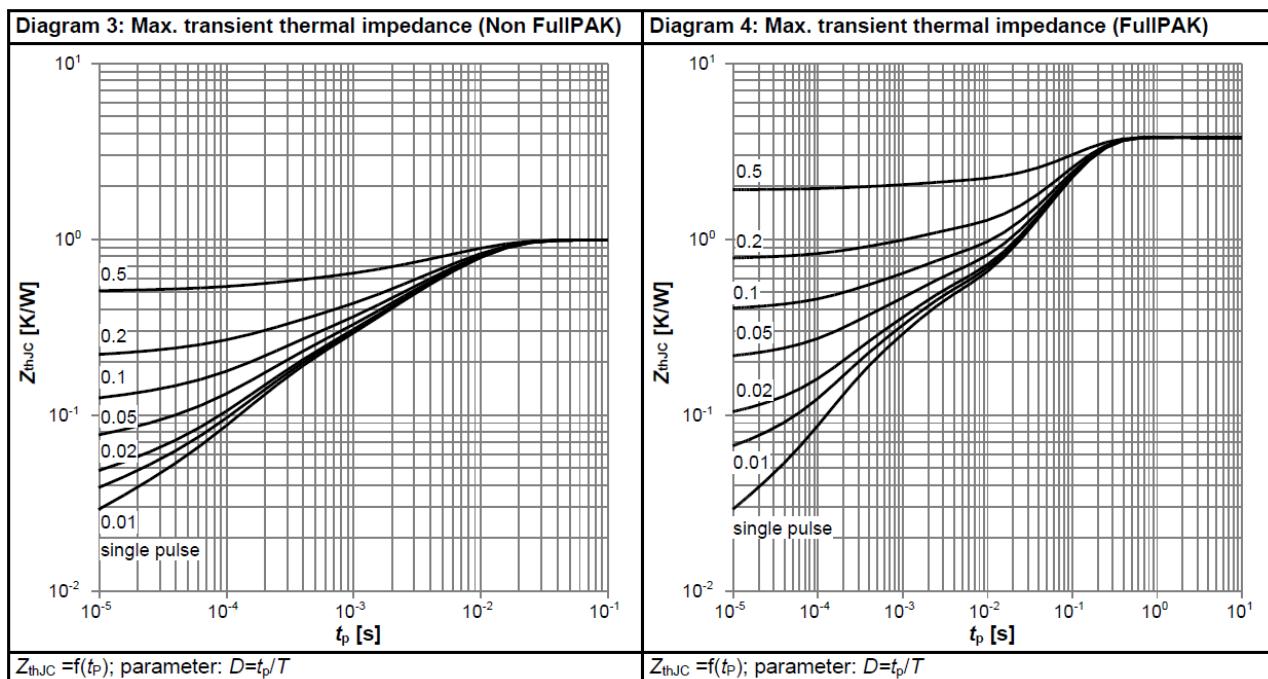
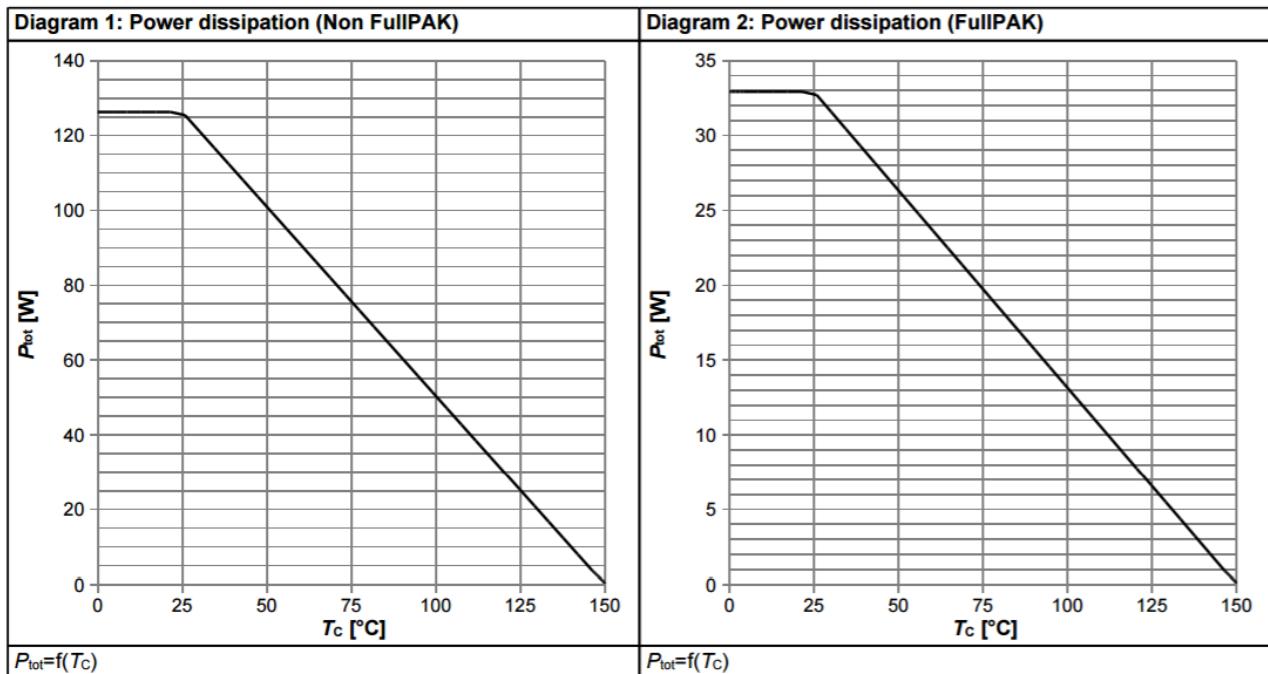
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
<b>Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA, T <sub>J</sub> = 25°C	600	--	--	V
		V <sub>GS</sub> = 0V, I <sub>D</sub> = 250μA, T <sub>J</sub> = 150°C	--	650	--	V
ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250μA, Referenced to 25°C	--	0.6	--	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 650V, V <sub>GS</sub> = 0V -T <sub>J</sub> = 150°C	-- 10	-- -	1	μA μA
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 30V, V <sub>DS</sub> = 0V	--	--	100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -30V, V <sub>DS</sub> = 0V	--	--	-100	nA
<b>On Characteristics</b>						
V <sub>G(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = 250μA	2.5	--	4.5	V
R <sub>D(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> = 9A	--	0.22	0.25	Ω
g <sub>F</sub> S	Forward Transconductance	V <sub>DS</sub> = 40V, I <sub>D</sub> = 9A	--	16	--	S
<b>Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V, f = 1.0MHz	--	1230	-	pF
C <sub>oss</sub>	Output Capacitance		--	30	-	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		--	2.6	--	pF
<b>Switching Characteristics</b>						
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 400V, I <sub>D</sub> = 9A R <sub>G</sub> = 20Ω (Note 4)	--	20	--	ns
t <sub>r</sub>	Turn-On Rise Time		--	17	--	ns
t <sub>d(off)</sub>	Turn-Off Delay Time		--	170	--	ns
t <sub>f</sub>	Turn-Off Fall Time		--	13	--	ns
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> = 400V, I <sub>D</sub> = 9A V <sub>GS</sub> = 10V (Note 4)	--	42	--	nC
Q <sub>gs</sub>	Gate-Source Charge		--	6	--	nC
Q <sub>gd</sub>	Gate-Drain Charge		--	29	--	nC
<b>Drain-Source Diode Characteristics and Maximum Ratings</b>						
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current	--	--	18	--	A
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current	--	--	42	--	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0V, I <sub>S</sub> = 9A	--	0.9	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0V, I <sub>S</sub> = 9A dI/dt = 100A/μs	--	380	--	ns
Q <sub>rr</sub>	Reverse Recovery Charge		--	4.5	--	μC

### NOTES:

- Repetitive Rating: Pulse width limited by maximum junction temperature
- L=60mH, I<sub>AS</sub>=4A, V<sub>DD</sub>=150V, Starting T<sub>J</sub>=25 °C
- I<sub>SD</sub><4.5A, dI/dt ≤ 200A/us, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25 °C
- Pulse Test: Pulse width ≤ 300us, Duty Cycle ≤ 2%
- Essentially Independent of Operating Temperature Typical Characteristics

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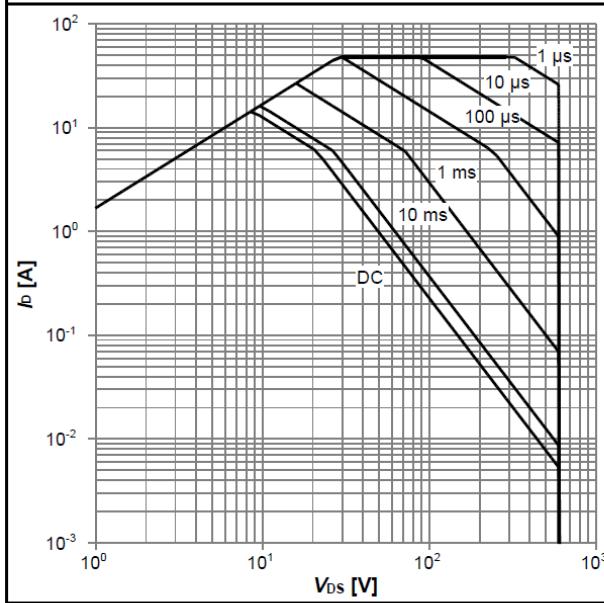
## Typical Performance Characteristics



# 650V 18A Power MOSFET

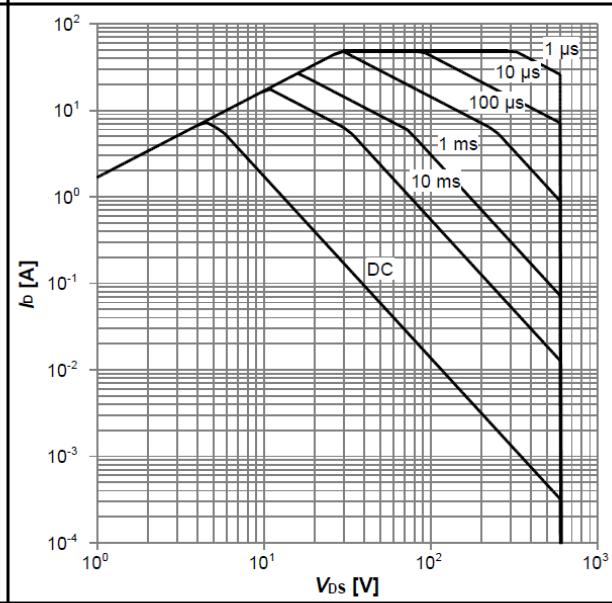
## Typical Performance Characteristics

Diagram 5: Safe operating area (Non FullPAK)



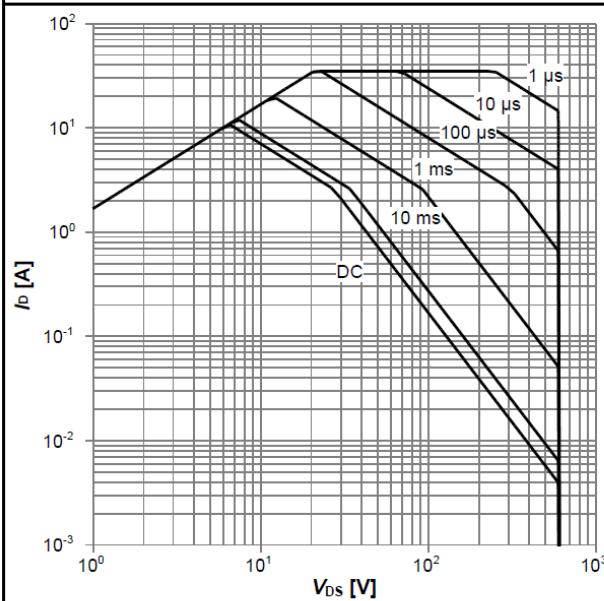
$I_D=f(V_{DS})$ ;  $T_C=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

Diagram 6: Safe operating area (FullPAK)



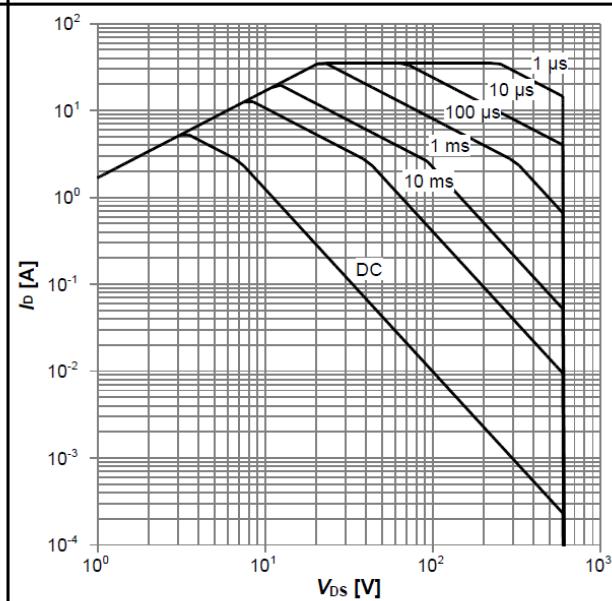
$I_D=f(V_{DS})$ ;  $T_C=25^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

Diagram 7: Safe operating area (Non FullPAK)



$I_D=f(V_{DS})$ ;  $T_C=80^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

Diagram 8: Safe operating area (FullPAK)

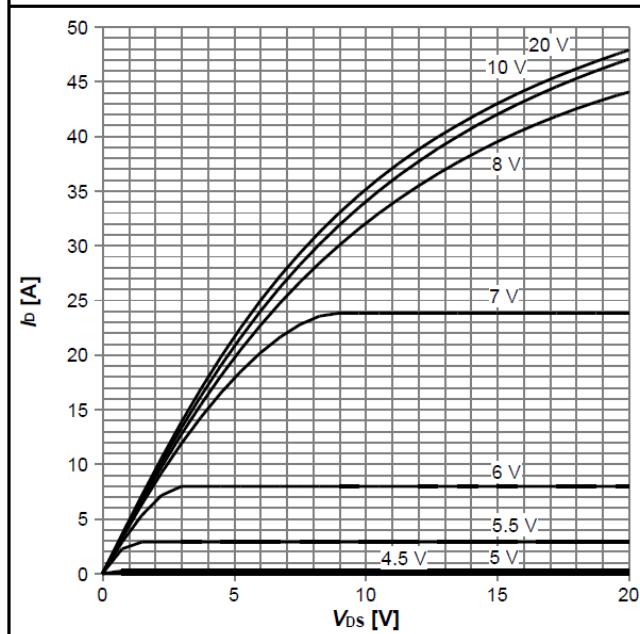


$I_D=f(V_{DS})$ ;  $T_C=80^\circ\text{C}$ ;  $D=0$ ; parameter:  $t_p$

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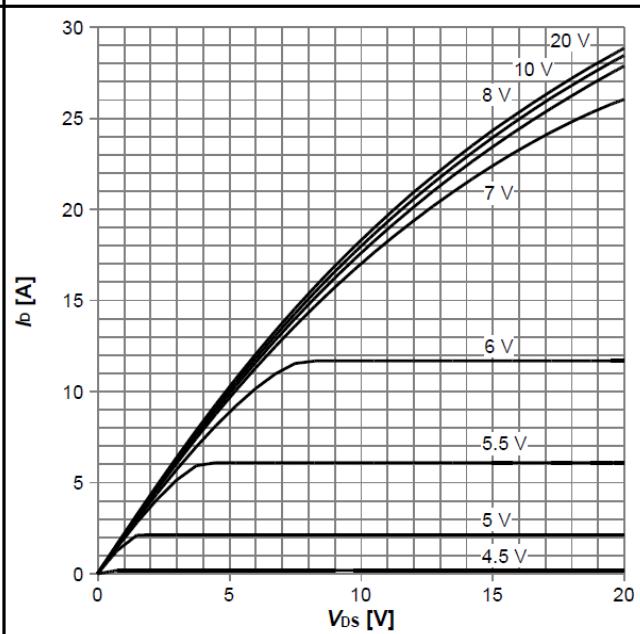
## Typical Performance Characteristics

Diagram 9: Typ. output characteristics



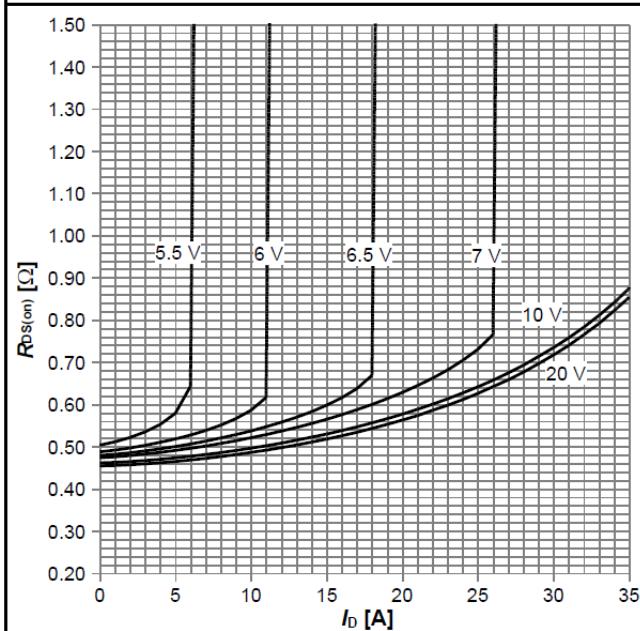
$I_D=f(V_{DS})$ ;  $T_j=25^\circ\text{C}$ ; parameter:  $V_{GS}$

Diagram 10: Typ. output characteristics



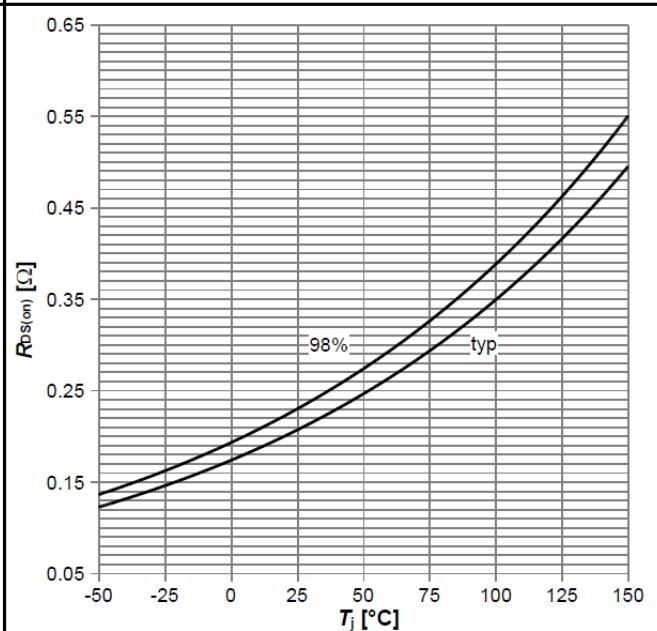
$I_D=f(V_{DS})$ ;  $T_j=125^\circ\text{C}$ ; parameter:  $V_{GS}$

Diagram 11: Typ. drain-source on-state resistance



$R_{DS(on)}=f(I_D)$ ;  $T_j=125^\circ\text{C}$ ; parameter:  $V_{GS}$

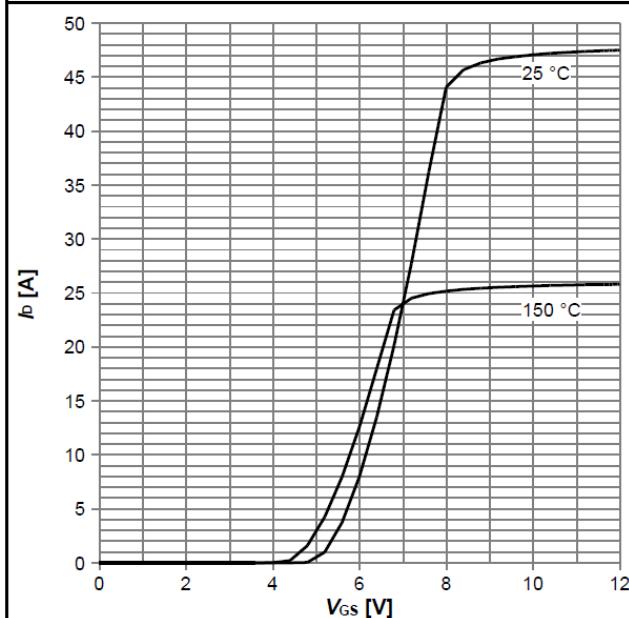
Diagram 12: Drain-source on-state resistance



$R_{DS(on)}=f(T_j)$ ;  $I_D=6.4$  A;  $V_{GS}=10$  V

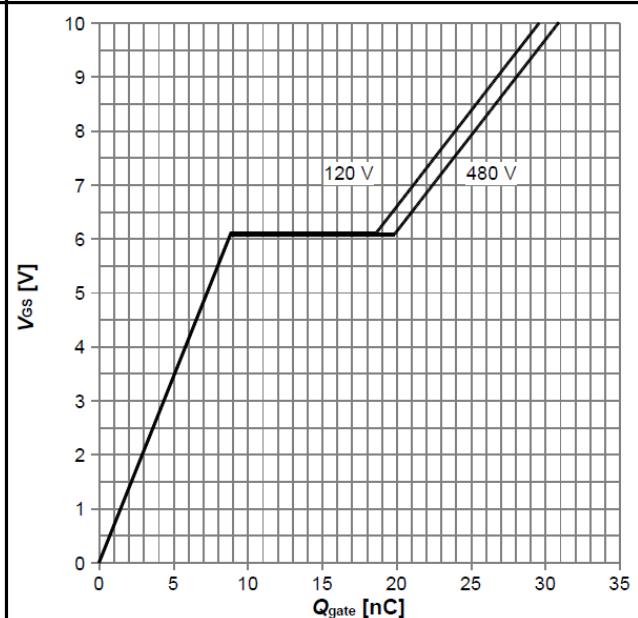
## Typical Performance Characteristics

Diagram 13: Typ. transfer characteristics



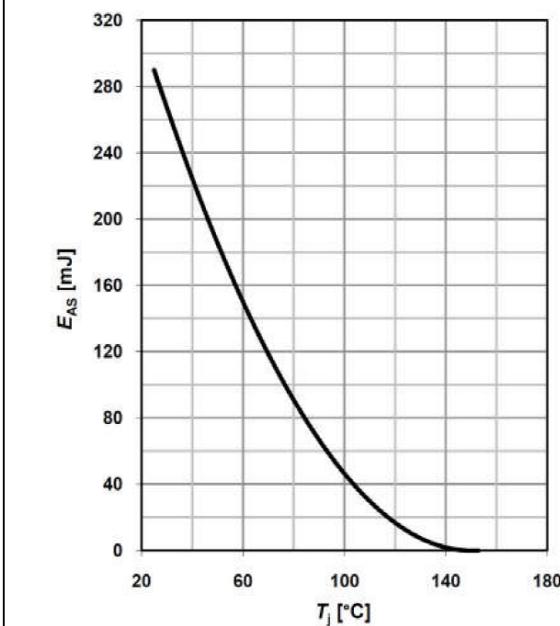
$I_D=f(V_{GS})$ ;  $V_{DS}=20\text{ V}$ ; parameter:  $T_j$

Diagram 14: Typ. gate charge



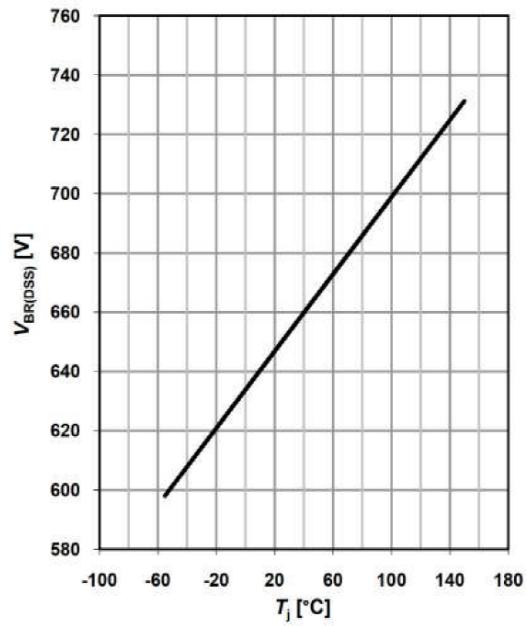
$V_{DS}=f(Q_{gate})$ ;  $I_D=8.0\text{ A}$  pulsed; parameter:  $V_{DD}$

Avalanche energy



$E_{AS}=f(T_j)$ ;  $I_D=2.4\text{ A}$ ;  $V_{DD}=50\text{ V}$

Drain-source breakdown voltage



$V_{BR(DSS)}=f(T_j)$ ;  $I_D=0.25\text{ mA}$

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Table 20 Switching times test circuit and waveform for inductive load

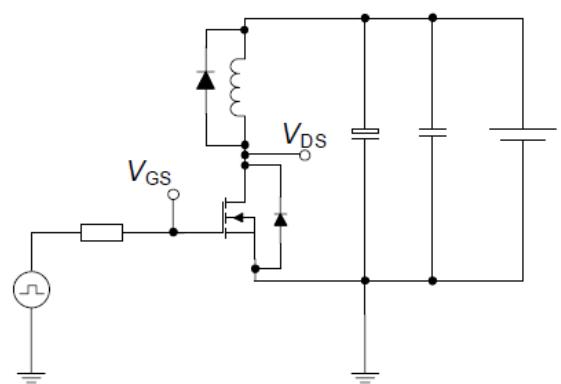
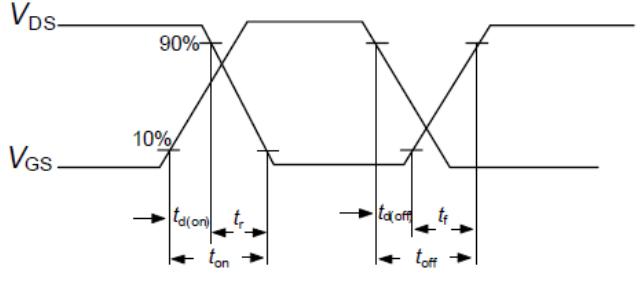
Switching times test circuit for inductive load	Switching time waveform
	

Table 21 Unclamped inductive load test circuit and waveform

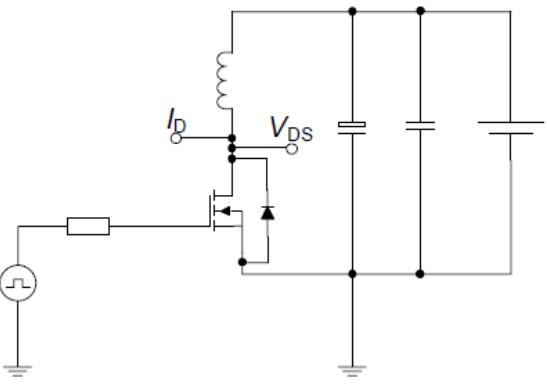
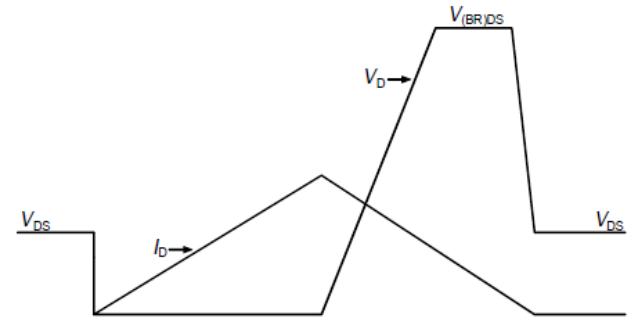
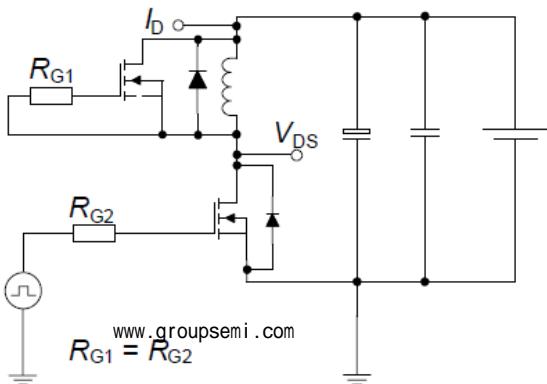
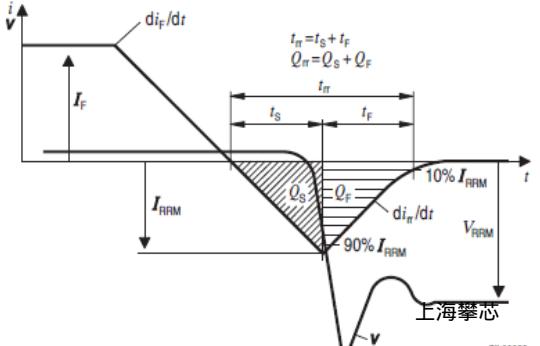
Unclamped inductive load test circuit	Unclamped inductive waveform
	

Table 22 Test circuit and waveform for diode characteristics

Test circuit for diode characteristics	Diode recovery waveform
 <p> <math>R_{G1} = R_{G2}</math>  <a href="http://www.groupsemi.com">www.groupsemi.com</a> </p>	 <p> <math>t_F = t_S + t_p</math>  <math>Q_n = Q_S + Q_F</math>  <math>t_r</math>  <math>t_d</math>  <math>Q_S</math>  <math>Q_F</math>  <math>I_F</math>  <math>I_{RRM}</math>  <math>V_{RRM}</math>  <math>10\% I_{RRM}</math>  <math>90\% I_{RRM}</math>  <math>v</math>  <math>i</math>  <math>t</math>          上海攀芯          SL00068       </p>